Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/679,697	LEE ET AL.	
Examiner	Art Unit	
Thei V. Duena	2971	

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Class	Subclass	Date	Examiner
349	190	03/16/05	30
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	73 74	03/18/05	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	03/16/05 03/17/05 03/18/05	9.D	
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